

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination INOUE ET AL.	
		Examiner A. Sefer	Art Unit 2826	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2005/0127394	06-2005	Nagahama et al.	257/103
	B	US-			
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	D	US-			
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	K	US-			
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	M	US-			

FOREIGN PATENT DOCUMENTS

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	N	JP 2001-196700	07-2001	Japan	Ozaki	
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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